

**Search Notes**

Application/Control No.

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Examiner

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Applicant(s)/Patent under  
Reexamination

ELBE ET AL.

Art Unit

2193

**SEARCHED**

Class	Subclass	Date	Examiner
708	491-492	7/13/2005	MAI

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Inventor search Double Patenting Check [with SN 10/623,830] Data Bases Search (see attached copy)	7/13/2005	MAI